



FQD1N60C / FQU1N60C

600V N-Channel MOSFET

General Description

These N-Channel enhancement mode power field effect transistors are produced using Fairchild's proprietary, planar stripe, DMOS technology.

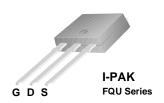
This advanced technology has been especially tailored to minimize on-state resistance, provide superior switching performance, and withstand high energy pulse in the avalanche and commutation mode. These devices are well suited for high efficiency switched mode power supplies, active power factor correction, electronic lamp ballasts based on half bridge topology.

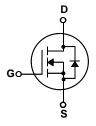
Features

- 1A, 600V, $R_{DS(on)} = 11.5\Omega @V_{GS} = 10 V$
- Low gate charge (typical 4.8nC)
- Low Crss (typical 3.5 pF)
- Fast switching
- 100% avalanche tested
- · Improved dv/dt capability
- RoHS Compliant









Absolute Maximum Ratings T_C = 25°C unless otherwise noted

Symbol	Parameter		FQD1N60C / FQU1N60C	Units
V _{DSS}	Drain-Source Voltage		600	V
I _D	Drain Current - Continuous (T _C = 25°C) - Continuous (T _C = 100°C)		1	Α
			0.6	Α
I _{DM}	Drain Current - Pulsed	(Note 1)	4	А
V _{GSS}	Gate-Source Voltage		± 30	V
E _{AS}	Single Pulsed Avalanche Energy	(Note 2)	33	mJ
I _{AR}	Avalanche Current	(Note 1)	1	Α
E _{AR}	Repetitive Avalanche Energy	(Note 1)	2.8	mJ
dv/dt	Peak Diode Recovery dv/dt	(Note 3)	4.5	V/ns
Power Dissipation (T _A = 25°C)*			2.5	W
P_D	Power Dissipation (T _C = 25°C)		28	W
	- Derate above 25°C		0.22	W/°C
T_J , T_{STG}	Operating and Storage Temperature Range		-55 to +150	°C
T _L	Maximum lead temperature for soldering purposes, 1/8" from case for 5 seconds		300	°C

Thermal Characteristics

Symbol	Parameter	Тур	Max	Units
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case		4.53	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient*		50	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient		110	°C/W

Symbol	Parameter	Test Conditions	Min	Тур	Max	Units
Off Cha	racteristics					
BV _{DSS}	Drain-Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$	600			V
ΔBV _{DSS} / ΔT _J	Breakdown Voltage Temperature Coefficient	$I_D = 250 \mu\text{A}$, Referenced to 25°C		0.6		V/°C
I _{DSS}	Zero Gate Voltage Drain Current	V _{DS} = 600 V, V _{GS} = 0 V			1	μΑ
		V _{DS} = 480 V, T _C = 125°C			10	μΑ
I _{GSSF}	Gate-Body Leakage Current, Forward	V _{GS} = 30 V, V _{DS} = 0 V			100	nA
I _{GSSR}	Gate-Body Leakage Current, Reverse	$V_{GS} = -30 \text{ V}, V_{DS} = 0 \text{ V}$			-100	nA
On Cha	racteristics					
V _{GS(th)}	Gate Threshold Voltage	V _{DS} = V _{GS} , I _D = 250 μA	2.0		4.0	V
R _{DS(on)}	Static Drain-Source On-Resistance	V _{GS} = 10 V, I _D = 0.5 A		9.3	11.5	Ω
9 _{FS}	Forward Transconductance	$V_{DS} = 40 \text{ V}, I_D = 0.5 \text{ A}$ (Note 4)		0.75		S
	ic Characteristics					_
C _{iss}	Input Capacitance	$V_{DS} = 25 \text{ V}, V_{GS} = 0 \text{ V},$		130	170	pF -
Coss	Output Capacitance	f = 1.0 MHz		19	25	pF
C _{rss}	Reverse Transfer Capacitance			3.5	4.5	pF
Switchi	ng Characteristics					
t _{d(on)}	Turn-On Delay Time	$V_{DD} = 300 \text{ V}, I_{D} = 1.1 \text{ A},$	-	7	24	ns
t _r	Turn-On Rise Time	$R_G = 25 \Omega$		21	52	ns
t _{d(off)}	Turn-Off Delay Time	- 1.6 - 1 - 1		13	36	ns
t _f	Turn-Off Fall Time	(Note 4, 5)		27	64	ns
Qg	Total Gate Charge	$V_{DS} = 480 \text{ V}, I_{D} = 1.1 \text{ A},$		4.8	6.2	nC
Q _{gs}	Gate-Source Charge	V _{GS} = 10 V		0.7		nC
Q _{gd}	Gate-Drain Charge	(Note 4, 5)		2.7		nC
Drain-S	ource Diode Characteristics a	nd Maximum Ratings				
I _S	Maximum Continuous Drain-Source Diode Forward Current				1	Α
I _{SM}	Maximum Pulsed Drain-Source Diode F	m Pulsed Drain-Source Diode Forward Current			4	Α
V_{SD}	Drain-Source Diode Forward Voltage	$V_{GS} = 0 \text{ V}, I_{S} = 0.5 \text{ A}$			1.4	V
t _{rr}	Reverse Recovery Time	$V_{GS} = 0 \text{ V}, I_{S} = 1.1 \text{ A},$		190		ns
Q _{rr}	Reverse Recovery Charge	$dI_F / dt = 100 A/\mu s$ (Note 4)		0.53		μC

- **Notes:**1. Repetitive Rating : Pulse width limited by maximum junction temperature 2. L = 59 mH, I $_{AS}$ = 1.1 A, V $_{DD}$ = 50V, R $_{G}$ = 25 Ω , Starting T $_{J}$ = 25°C 3. I $_{SD}$ ≤ 1.1 A, di/dt ≤ 200A/ $_{HS}$, V $_{DD}$ ≤ BV $_{DSS}$, Starting T $_{J}$ = 25°C 4. Pulse Test : Pulse width ≤ 300 $_{HS}$, Duty cycle ≤ 2% 5. Essentially independent of operating temperature

Typical Characteristics

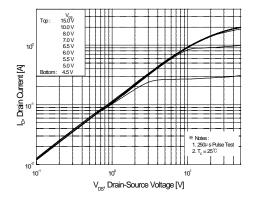


Figure 1. On-Region Characteristics

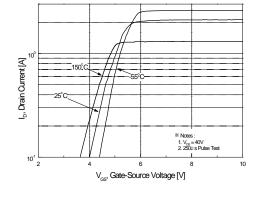


Figure 2. Transfer Characteristics

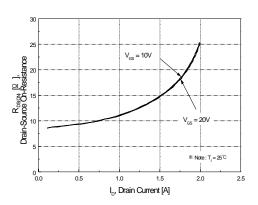


Figure 3. On-Resistance Variation vs Drain Current and Gate Voltage

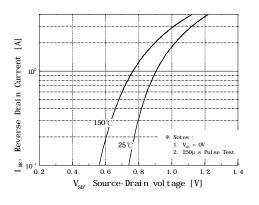


Figure 4. Body Diode Forward Voltage Variation with Source Current and Temperature

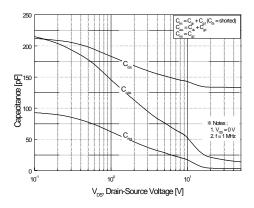


Figure 5. Capacitance Characteristics

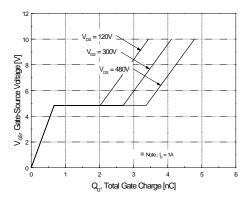
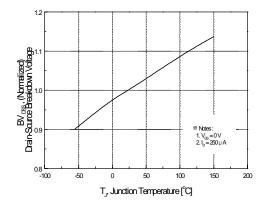


Figure 6. Gate Charge Characteristics

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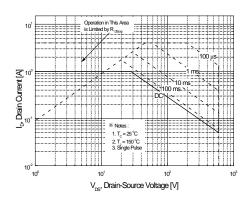
Typical Characteristics (Continued)



30 25 25 20 20 25 20 25 20 25 20 25 20 25 20 25 20 25 20 25 20 20 25 20 20 20 20 20 20 20 20 20 20 20

Figure 7. Breakdown Voltage Variation vs Temperature

Figure 8. On-Resistance Variation vs Temperature



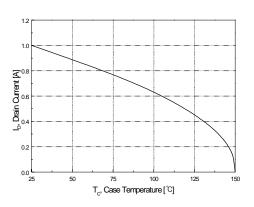


Figure 9. Maximum Safe Operating Area

Figure 10. Maximum Drain Current vs Case Temperature

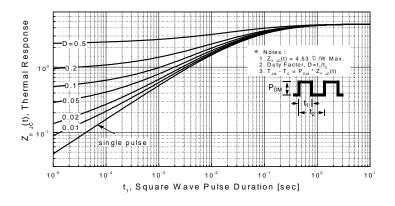
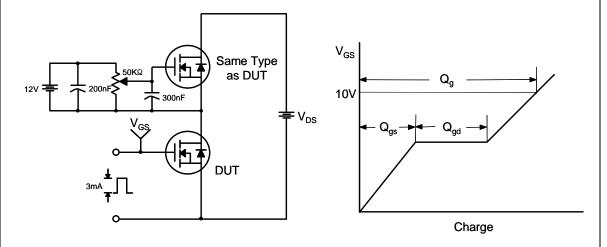


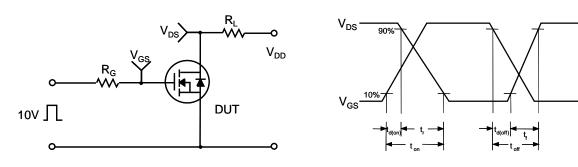
Figure 11. Transient Thermal Response Curve

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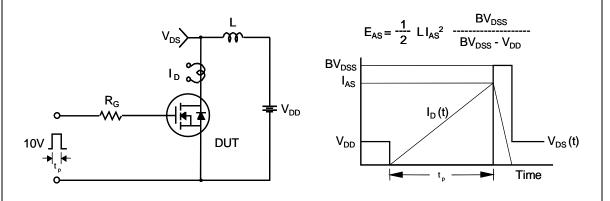
Gate Charge Test Circuit & Waveform



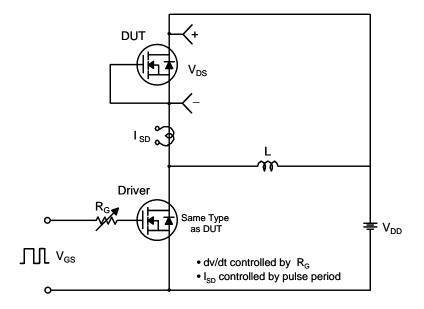
Resistive Switching Test Circuit & Waveforms

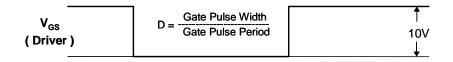


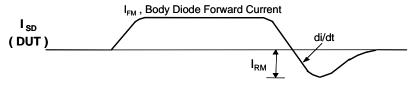
Unclamped Inductive Switching Test Circuit & Waveforms



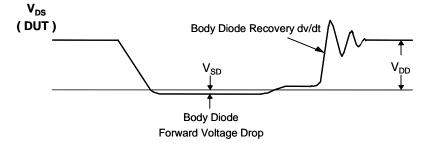
Peak Diode Recovery dv/dt Test Circuit & Waveforms







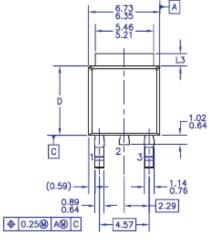
Body Diode Reverse Current

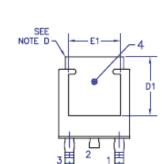


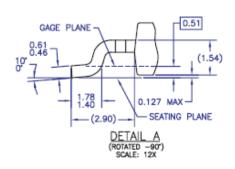
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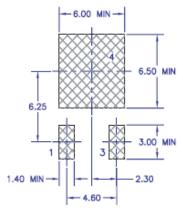
Mechanical Dimensions

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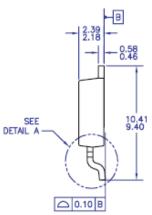








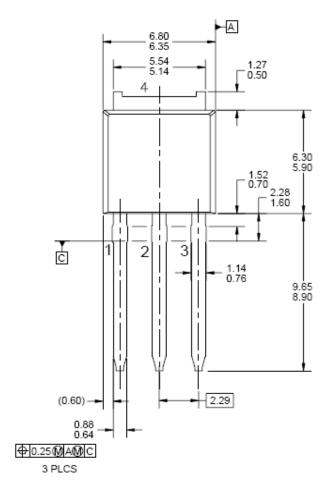
LAND PATTERN RECOMMENDATION

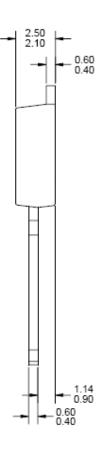


Dimensions in Millimeters

Mechanical Dimensions

I - PAK







Dimensions in Millimeters





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